## PATENT ABSTRACTS OF JAPAN

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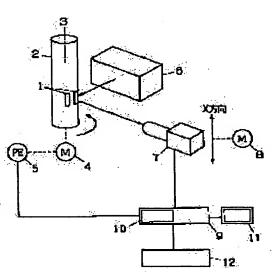
## (54) EQUIPMENT AND METHOD FOR SURFACE INSPECTION

07.09.1994

## (57)Abstract:

PURPOSE: To provide a method and equipment for surface inspection which detects surface-defects different in reflection characteristics by a very simple construction, accurately, efficiently and in a very short time.

CONSTITUTION: A plurality of detection areas 1 are set on the surface of a photoreceptor drum 2 in the direction of movement thereof. When each detection area 1 is illuminated by a light source 6, reflected lights having different scattering angles respectively are cast on a CCD camera 7. The CCD camera 7 has a two-dimensional area sensor and the lights reflected from each detection area 1 and being different in the scattering angle are received respectively by a plurality of light receiving regions set on one area sensor. A defect is detected in a defect determining part 9 on the basis of a signal of each light receiving region and in accordance with parameters set for each detection area 1. In a computer 12, identification of the defect detected for each detection area 1. determination of assortment of the defects different in reflection characteristics, determination of acceptance/reject of the photoreceptor drum 2, etc., are executed.



## **LEGAL STATUS**

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